

**Notice of References Cited**

Application/Control No.

09/576,681

Applicant(s)/Patent Under  
Reexamination  
CHIBA ET AL.

Examiner

Lynne R. Edmondson

Art Unit

1725

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*	D	US-5463200-	10-1995	James et al.	219	121.68
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**NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a) )  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign